AN78xx/AN78xxF Series

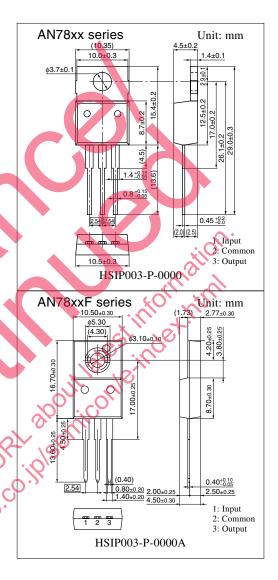
3-pin positive output voltage regulator (1 A type)

Overview

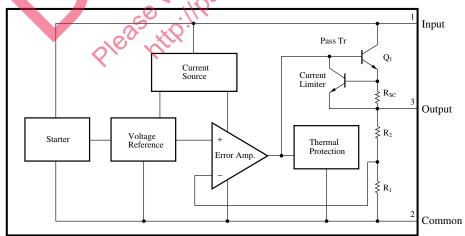
The AN78xx series and the AN78xxF series are 3-pin, fixed positive output type monolithic voltage regulators. Stabilized fixed output voltage is obtained from unstable DC input voltage without using any external components. 11 types of fixed output voltage are available; 5V, 6V, 7V, 8V, 9V, 10V, 12V, 15V, 18V, 20V, and 24V. They can be used widely in power circuits with current capacity of up to 1A.

■ Features

- No external components
- Output voltage: 5V,6V,7V,8V,9V,10V,12V,15V,18V, 20V,24V
- Built-in overcurrent limit circuit
- Built-in thermal overload protection circuit
- Built-in ASO (area of safe operation) protection circuit



■ Block Diagram



■ Absolute Maximum Ratings at $T_a = 25$ °C

Parameter		Symbol	Rating		Unit	
Input voltage		V	35 *1		V	
		$V_{\rm I}$	40 *2		V	
D 1' ' '	AN78xx series	D	15 *3		W	
Power dissipation	AN78xxF series	P_{D}	10.25 *3		W	
Operating ambient	Operating ambient temperature		-30 to +80		°C	
Storage temperature		T_{stg}	-55 to +150		°C	

^{*1} AN7805/F, AN7806/F, AN7807/F, AN7808/F, AN7809/F, AN7810/F, AN7812/F, AN7815/F, AN7818/F

■ Electrical Characteristics at $T_a = 25$ °C

• AN7805, AN7805F (5V type)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Output voltage	V_{O}	$T_j = 25^{\circ}C$	4.8	5	5.2	V
Output voltage tolerance	Vo	$V_1 = 8 \text{ to } 20V, I_0 = 5\text{mA to } 1A,$ $T_j = 0 \text{ to } 125^{\circ}\text{C}, P_D \le *$	4.75	_	5.25	V
Line regulation	REG_{IN}	$V_I = 7.5 \text{ to } 25 \text{ V}, T_j = 25^{\circ}\text{C}$		3	100	mV
		$V_I = 8 \text{ to } 12V, T_j = 25^{\circ}C$, QU	50	mV
Load regulation	REG_L	$I_0 = 5 \text{mA to } 1.5 \text{A}, T_j = 25 ^{\circ} \text{C}$	x	15 -	100	mV
Load regulation	I	$I_0 = 250$ to 750mA, $T_j = 25^{\circ}$ C		- 26	50	mV
Bias current	I_{Bias}	$T_j = 25$ °C		3.9	8	mA
Bias current fluctuation to input	$\Delta I_{Bias(IN)}$	$V_I = 7.5 \text{ to } 25\text{V}, T_j = 25^{\circ}\text{C}$	10-16	<i>5</i> —	1.3	mA
Bias current fluctuation to load	$\Delta I_{Bias(L)}$	$I_0 = 5 \text{mA to } 1 \text{A}, T_j = 25 ^{\circ} \text{C}$	9		0.5	mA
Output noise voltage	V _{no}	f = 10Hz to 100kHz		40		μV
Ripple rejection ratio	RR	$V_1 = 8$ to 18V, $I_0 = 100$ mA, $f = 120$ Hz	62			dB
Minimum input/output voltage difference	$V_{\mathrm{DIF}(\mathrm{min})}$	$I_0 = 1A, T_j = 25^{\circ}C$		2		V
Output impedance	Zo	f = 1kHz		17		mΩ
Output short-circuit current	I _{O(Short)}	$V_{\rm I} = 25V, T_{\rm j} = 25^{\circ}C$		700		mA
Peak output current	$I_{O(Peak)}$	$T_i = 25^{\circ}C$		2		A
Output voltage temperature coefficient	$\Delta V_{O}/T_{a}$	$I_0 = 5 \text{mA}, T_1 = 0 \text{ to } 125^{\circ}\text{C}$		- 0.3		mV/°C

Note 1) The specified condition $T_j = 25^{\circ}C$ means that the test should be carried out within so short a test time (within 10ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

^{*2} AN7820/F, AN7824/F

^{*3} Follow the derating curve. When T_j exceeds 150°C, the internal circuit cuts off the output.

Note 2) Unless otherwise specified, $V_I = 10V$, $I_O = 500 \text{mA}$, $C_I = 0.33 \mu \text{F}$ and $C_O = 0.1 \mu \text{F}$. * AN78xx series: 15W, AN78xxF series: 10.25W

• AN7806, 7806F (6V type)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Output voltage	Vo	$T_j = 25^{\circ}C$	5.75	6	6.25	V
Output voltage tolerance	Vo	$V_I = 9 \text{ to } 21V, I_O = 5\text{mA to } 1A,$ $T_j = 0 \text{ to } 125^{\circ}\text{C}, P_D \le *$	5.7		6.3	V
Line regulation	REG_{IN}	$V_I = 8.5 \text{ to } 25V, T_j = 25^{\circ}C$		5	120	mV
Line regulation	KEOIN	$V_I = 9 \text{ to } 13V, T_j = 25^{\circ}C$		1.5	60	mV
Load regulation	REG_L	$I_0 = 5 \text{mA to } 1.5 \text{A}, T_j = 25 ^{\circ} \text{C}$	_	14	120	mV
Load regulation	KEUL	$I_0 = 250 \text{ to } 750 \text{mA}, T_j = 25^{\circ}\text{C}$		4	60	mV
Bias current	I_{Bias}	$T_j = 25^{\circ}C$		3.9	8	mA
Bias current fluctuation to input	$\Delta I_{Bias(IN)}$	$V_I = 8.5 \text{ to } 25\text{V}, T_j = 25^{\circ}\text{C}$			1.3	mA
Bias current fluctuation to load	$\Delta I_{Bias(L)}$	$I_0 = 5 \text{mA to } 1 \text{A}, T_j = 25^{\circ} \text{C}$			0.5	mA
Output noise voltage	V_{no}	f = 10Hz to 100 kHz		40	-	μV
Ripple rejection ratio	RR	$V_I = 9 \text{ to } 19V, I_0 = 100\text{mA}, f = 120\text{Hz}$	59			dB
Minimum input/output voltage difference	$V_{\text{DIF}(\text{min})}$	$I_0 = 1A, T_j = 25^{\circ}C$		2		V
Output impedance	Zo	f = 1kHz	1	17	. ~	mΩ
Output short-circuit current	I _{O(Short)}	$V_I = 25V, T_j = 25^{\circ}C$		700	Lib	mA
Peak output current	I _{O(Peak)}	$T_j = 25^{\circ}C$		2.0	00-7	A
Output voltage temperature coefficient	$\Delta V_{O}/T_{a}$	$I_0 = 5 \text{mA}, T_i = 0 \text{ to } 125^{\circ}\text{C}$		€ 0.4	#1	mV/°C

Note 1) The specified condition $T_j = 25^{\circ}$ C means that the test should be carried out within so short a test time (within 10ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

Note 2) Unless otherwise specified, $V_1 = 11V$, $I_0 = 500$ mA, $C_1 = 0.33\mu$ F and $C_0 = 0.1\mu$ F.

• AN7807, 7807F (7V type)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Output voltage	Vo	T _j =25°C	6.7	7	7.3	V
Output voltage tolerance	Vo	$V_I = 10 \text{ to } 22\text{V}, I_O = 5\text{mA to } 1\text{A}, T_j = 0 \text{ to } 125^{\circ}\text{C}, P_D \le *$	6.6	_	7.4	V
Line regulation	REG _{IN}	$V_I = 9.5$ to 25V, $T_i = 25$ °C	·——	5	140	mV
Life regulation	KEOIN	$V_1 = 10 \text{ to } 15\text{V}, T_j = 25^{\circ}\text{C}$	· 	1.5	70	mV
Londragulation	REG _L	$I_0 = 5$ mA to 1.5A, $T_j = 25$ °C		14	140	mV
Load regulation	KEUL	$I_0 = 250$ to 750mA, $T_j = 25$ °C		4	70	mV
Bias current	I_{Bias}	T ₀ = 25°C		3.9	8	mA
Bias current fluctuation to input	$\Delta I_{Bias(IN)}$	$V_I = 9.5 \text{ to } 25V, T_j = 25^{\circ}C$			1	mA
Bias current fluctuation to load	$\Delta I_{\mathrm{Bias}(L)}$	$I_0 = 5 \text{mA to } 1 \text{A}, T_j = 25^{\circ} \text{C}$			0.5	mA
Output noise voltage	V _{no}	f = 10Hz to $100kHz$		46		μV
Ripple rejection ratio	RR	$V_I = 10 \text{ to } 20V, I_O = 100\text{mA}, f = 120\text{Hz}$	57			dB
Minimum input/output voltage difference	V _{DIF(min)}	$I_0 = 1A, T_j = 25^{\circ}C$		2		V
Output impedance	Zo	f = 1kHz		16		mΩ
Output short-circuit current	I _{O(Short)}	$V_I = 25V, T_j = 25^{\circ}C$		700		mA
Peak output current	I _{O(Peak)}	$T_j = 25^{\circ}C$		2		A
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_0 = 5 \text{mA}, T_j = 0 \text{ to } 125^{\circ}\text{C}$		- 0.5		mV/°C

Note 1) The specified condition $T_j = 25^{\circ}\text{C}$ means that the test should be carried out within so short a test time (within 10ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

^{*} AN78xx series: 15W, AN78xxF series: 10.25W

Note 2) Unless otherwise specified, $V_I = 12V$, $I_O = 500$ mA, $C_I = 0.33\mu$ F and $C_O = 0.1\mu$ F.

^{*} AN78xx series: 15W, AN78xxF series: 10.25W

• AN7808, 7808F (8V type)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Output voltage	$V_{\rm O}$	$T_j = 25^{\circ}C$	7.7	8	8.3	V
Output voltage tolerance	Vo	$V_I = 11 \text{ to } 23V, I_O = 5\text{mA to } 1A, \\ T_j = 0 \text{ to } 125^{\circ}\text{C}, P_D \le *$	7.6		8.4	V
Line regulation	REG _{IN}	$V_I = 10.5 \text{ to } 25\text{V}, T_j = 25^{\circ}\text{C}$		6	160	mV
Ellic regulation	KEGIN	$V_I = 11 \text{ to } 17V, T_j = 25^{\circ}C$		2	80	mV
Load regulation	REG	$I_0 = 5 \text{mA to } 1.5 \text{A}, T_j = 25 ^{\circ} \text{C}$	_	12	160	mV
Load regulation	KEOL	$I_0 = 250 \text{ to } 750 \text{mA}, T_j = 25^{\circ}\text{C}$		4	80	mV
Bias current	I_{Bias}	$T_j = 25^{\circ}C$		3.9	8	mA
Bias current fluctuation to input	$\Delta I_{Bias(IN)}$	$V_I = 10.5 \text{ to } 25V, T_j = 25^{\circ}C$			1	mA
Bias current fluctuation to load	$\Delta I_{Bias(L)}$	$I_0 = 5 \text{mA to } 1 \text{A}, T_j = 25^{\circ} \text{C}$			0.5	mA
Output noise voltage	V_{no}	f = 10Hz to 100 kHz		52	-	μV
Ripple rejection ratio	RR	$V_1 = 11.5$ to 21.5V, $I_0 = 100$ mA, $f = 120$ Hz	56			dB
Minimum input/output voltage difference	$V_{\text{DIF}(\text{min})}$	$I_0 = 1A$, $T_j = 25$ °C		2		V
Output impedance	Zo	f = 1kHz	17	16	3	mΩ
Output short-circuit current	I _{O(Short)}	$V_I = 25V, T_j = 25^{\circ}C$		700	A TO	mA
Peak output current	I _{O(Peak)}	$T_j = 25^{\circ}C$		2.0	0 <u> </u>	A
Output voltage temperature coefficient	$\Delta V_{O}/T_{a}$	$I_0 = 5\text{mA}, T_j = 0 \text{ to } 125^{\circ}\text{C}$		€ 0.5	#	mV/°C

Note 1) The specified condition $T_j = 25^{\circ}$ C means that the test should be carried out within so short a test time (within 10ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

Note 2) Unless otherwise specified, $V_1 = 14V$, $I_0 = 500$ mA, $C_1 = 0.33$ µF and $C_0 = 0.1$ µF.

AN7809, 7809F (9V type)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Output voltage	y_0	$T_j = 25^{\circ}C$	8.65	9	9.35	V
Output voltage tolerance	Vo	$V_I = 12 \text{ to } 24\text{V}, I_0 = 5\text{mA to } 1\text{A}, T_j = 0 \text{ to } 125^{\circ}\text{C}, P_D \leq *$	8.55		9.45	V
Line regulation	REG _{IN}	$V_I = 11.5 \text{ to } 26V_C T_{ij} = 25^{\circ}C$		7	180	mV
Ellic regulation	REGIN	$V_I = 12 \text{ to } 18V, T_j = 25^{\circ}C$		2	90	mV
Load ragulation	REG _L 🛠	$I_0 = 5 \text{mA to } 1.5 \text{A}, T_j = 25 ^{\circ} \text{C}$		12	180	mV
Load regulation	KEOL	$I_0 = 250 \text{ to } 750 \text{mA}, T_j = 25^{\circ}\text{C}$		4	90	mV
Bias current	IBias	T; = 25°C		3.9	8	mA
Bias current fluctuation to input	$\Delta I_{\mathrm{Bias(IN)}}$	$V_I = 11.5 \text{ to } 26\text{V}, T_j = 25^{\circ}\text{C}$			1	mA
Bias current fluctuation to load	$\Delta I_{Bias(L)}$	$I_0 = 5 \text{mA to } 1 \text{A}, T_j = 25 ^{\circ} \text{C}$			0.5	mA
Output noise voltage	V _{no}	f = 10Hz to 100kHz		57		μV
Ripple rejection ratio	RR	$V_I = 12 \text{ to } 22V, I_O = 100\text{mA}, f = 120\text{Hz}$	56			dB
Minimum input/output voltage difference	V _{DIF(min)}	$I_0 = 1A, T_j = 25^{\circ}C$		2		V
Output impedance	Zo	f = 1kHz		16		mΩ
Output short-circuit current	I _{O(Short)}	$V_I = 26V, T_j = 25^{\circ}C$		700	_	mA
Peak output current	I _{O(Peak)}	$T_j = 25^{\circ}C$		2		A
Output voltage temperature coefficient	$\Delta V_{O}/T_{a}$	$I_0 = 5 \text{mA}, T_j = 0 \text{ to } 125^{\circ}\text{C}$		- 0.5		mV/°C

Note 1) The specified condition $T_j = 25^{\circ}$ C means that the test should be carried out within so short a test time (within 10ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

^{*} AN78xx series: 15W, AN78xxF series: 10.25W

Note 2) Unless otherwise specified, $V_I = 15V$, $I_O = 500 \text{mA}$, $C_I = 0.33 \mu F$ and $C_O = 0.1 \mu F$.

^{*} AN78xx series: 15W, AN78xxF series: 10.25W

■ Electrical Characteristics at $T_a = 25$ °C (continued)

• AN7810, 7810F (10V type)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Output voltage	$V_{\rm o}$	$T_j = 25^{\circ}C$	9.6	10	10.4	V
Output voltage tolerance	Vo	$V_I = 13 \text{ to } 25\text{V}, I_O = 5\text{mA to } 1\text{A}, \\ T_j = 0 \text{ to } 125^{\circ}\text{C}, P_D \le *$	9.5		10.5	V
Line regulation	REG_{IN}	$V_I = 12.5 \text{ to } 27V, T_j = 25^{\circ}C$		8	200	mV
Line regulation	KEOIN	$V_I = 13 \text{ to } 19V, T_j = 25^{\circ}C$	-	2.5	100	mV
Load regulation	REG_L	$I_0 = 5 \text{mA to } 1.5 \text{A}, T_j = 25 ^{\circ} \text{C}$	_	12	200	mV
Load regulation	KEUL	$I_0 = 250 \text{ to } 750 \text{mA}, T_j = 25^{\circ}\text{C}$		4	100	mV
Bias current	I_{Bias}	$T_j = 25^{\circ}C$		3.9	8	mA
Bias current fluctuation to input	$\Delta I_{Bias(IN)}$	$V_I = 12.5 \text{ to } 27V, T_j = 25^{\circ}C$			1	mA
Bias current fluctuation to load	$\Delta I_{Bias(L)}$	$I_0 = 5 \text{mA to } 1 \text{A}, T_j = 25 ^{\circ} \text{C}$			0.5	mA
Output noise voltage	V_{no}	f = 10Hz to 100 kHz		63	-	μV
Ripple rejection ratio	RR	$V_I = 13 \text{ to } 23V, I_O = 100\text{mA}, f = 120\text{Hz}$	56			dB
Minimum input/output voltage difference	$V_{\text{DIF}(\text{min})}$	$I_0 = 1A, T_j = 25^{\circ}C$		2		V
Output impedance	Zo	f = 1kHz	1-	16	0	mΩ
Output short-circuit current	I _{O(Short)}	$V_I = 27V, T_j = 25^{\circ}C$		700	ALC:	mA
Peak output current	I _{O(Peak)}	$T_j = 25^{\circ}C$		2.0	00-7	A
Output voltage temperature coefficient	$\Delta V_{O}/T_{a}$	$I_0 = 5\text{mA}, T_j = 0 \text{ to } 125^{\circ}\text{C}$		€ 0.6	#()	mV/°C

Note 1) The specified condition $T_j = 25^{\circ}C$ means that the test should be carried out within so short a test time (within 10ms) that the characteristic value drift due to the chip junction temperature rise can be ignored. Note 2) Unless otherwise specified, $V_I=16$ V, $I_0=500$ mA, $C_I=0.33\mu F$ and $C_0=0.1\mu F$.

• AN7812, 7812F (12V type)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Output voltage	Vo	$T_j = 25^{\circ}C$	11.5	12	12.5	V
Output voltage tolerance	Vo	$V_1 = 15 \text{ to } 27\text{V}, I_0 = 5\text{mA to } 1\text{A}, T_j = 0 \text{ to } 125^{\circ}\text{C}, P_D \le {}^{*}\text{C}$	11.4		12.6	V
Line regulation	REG _{IN}	$V_I = 14.5 \text{ to } 30 \text{V} \cdot T_j = 25^{\circ} \text{C}$		10	240	mV
Effic regulation	KEOIN	$V_1 = 16 \text{ to } 22V$, $T_j = 25^{\circ}\text{C}$		3	120	mV
Lord regulation	REG _L	$I_0 = 5 \text{mA to } 1.5 \text{A}, T_j = 25 ^{\circ} \text{C}$		12	240	mV
Load regulation	KEUL	$I_0 = 250$ to 750mA, $T_j = 25$ °C		4	120	mV
Bias current	$I_{ m Bias}$	$T_{\rm i} = 25^{\circ}{\rm C}$		4	8	mA
Bias current fluctuation to input	ΔI _{Bias(IN)}	$V_I = 14.5 \text{ to } 30\text{V}, T_j = 25^{\circ}\text{C}$			1	mA
Bias current fluctuation to load	$\Delta I_{ ext{Bias(L)}}$	$I_0 = 5 \text{mA to } 1 \text{A}, T_j = 25^{\circ} \text{C}$			0.5	mA
Output noise voltage	V _{no}	f = 10Hz to 100kHz		75		μV
Ripple rejection ratio	RR	$V_I = 15 \text{ to } 25V, I_O = 100\text{mA}, f = 120\text{Hz}$	55			dB
Minimum input/output voltage difference	$V_{\text{DIF}(min)}$	$I_0 = 1A, T_j = 25^{\circ}C$		2		V
Output impedance	Zo	f = 1kHz		18		mΩ
Output short-circuit current	I _{O(Short)}	$V_I = 30V, T_j = 25^{\circ}C$		700		mA
Peak output current	I _{O(Peak)}	$T_j = 25^{\circ}C$		2		A
Output voltage temperature coefficient	$\Delta V_{O}/T_{a}$	$I_0 = 5 \text{mA}, T_j = 0 \text{ to } 125^{\circ}\text{C}$	_	- 0.8	_	mV/°C

Note 1) The specified condition $T_i = 25^{\circ}$ C means that the test should be carried out within so short a test time (within 10ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

AN78xx series: 15W, AN78xxF series: 10.25W

Note 2) Unless otherwise specified, $V_I = 19V$, $I_O = 500 \text{mA}$, $C_I = 0.33 \mu\text{F}$ and $C_O = 0.1 \mu\text{F}$.

AN78xx series: 15W, AN78xxF series: 10.25W

• AN7815, 7815F (15V type)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Output voltage	$V_{\rm o}$	$T_j = 25^{\circ}C$	14.4	15	15.6	V
Output voltage tolerance	V_{0}	$V_I = 18 \text{ to } 30\text{V}, I_O = 5\text{mA to } 1\text{A}, \\ T_j = 0 \text{ to } 125^{\circ}\text{C}, P_D \le *$	14.25		15.75	V
Line regulation	REG_{IN}	$V_I = 17.5 \text{ to } 30V, T_j = 25^{\circ}C$		11	300	mV
	KLOIN	$V_I = 20 \text{ to } 26V, T_j = 25^{\circ}C$		3	150	mV
Load regulation	REG _L	$I_0 = 5 \text{mA to } 1.5 \text{A}, T_j = 25 ^{\circ}\text{C}$		12	300	mV
Load regulation	KEUL	$I_0 = 250 \text{ to } 750 \text{mA}, T_j = 25^{\circ}\text{C}$		4	150	mV
Bias current	I_{Bias}	$T_j = 25^{\circ}C$		4	8	mA
Bias current fluctuation to input	$\Delta I_{Bias(IN)}$	$V_I = 17.5 \text{ to } 30V, T_j = 25^{\circ}C$			1	mA
Bias current fluctuation to load	$\Delta I_{Bias(L)}$	$I_0 = 5 \text{mA to } 1 \text{A}, T_j = 25^{\circ} \text{C}$			0.5	mA
Output noise voltage	V_{no}	f = 10Hz to 100 kHz		90		μV
Ripple rejection ratio	RR	$V_I = 18.5 \text{ to } 28.5 \text{V}, f = 120 \text{Hz}$	54			dB
Minimum input/output voltage difference	$V_{\text{DIF}(\text{min})}$	$I_0 = 1A, T_j = 25^{\circ}C$		2		V
Output impedance	Zo	f = 1kHz	1	19	0	mΩ
Output short-circuit current	I _{O(Short)}	$V_I = 30V, T_j = 25^{\circ}C$		700	ALC:	mA
Peak output current	I _{O(Peak)}	$T_j = 25^{\circ}C$		2.0	00-7	A
Output voltage temperature coefficient	$\Delta V_{O}/T_{a}$	$I_0 = 5\text{mA}, T_i = 0 \text{ to } 125^{\circ}\text{C}$		(⊝)	**	mV/°C

Note 1) The specified condition $T_j = 25^{\circ}$ C means that the test should be carried out within so short a test time (within 10ms) that the characteristic value drift due to the chip junction temperature rise can be ignored. Note 2) Unless otherwise specified, $V_1 = 23 \text{ V}$, $I_0 = 500 \text{mA}$, $C_1 = 0.33 \mu\text{F}$ and $C_0 = 0.1 \mu\text{F}$. * AN78xx series: 15W, AN78xxF series: 10.25W

• AN7818, 7818F (18V type)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Output voltage	V_0	$T_j = 25^{\circ}C$	17.3	18	18.7	V
Output voltage tolerance	Vo	$V_1 = 21 \text{ to } 33\text{ V}, I_0 = 5\text{mA to } 1\text{A}, $ $T_j = 0 \text{ to } 125^{\circ}\text{C}, P_D \le {}^{*}\text{C}$	17.1		18.9	V
Line regulation	REG _{IN}	$V_I = 21$ to 33V, $T_i = 25$ °C		14	360	mV
Line regulation	REGIN	$V_1 = 24 \text{ to } 30 \text{V}$, $T_j = 25^{\circ}\text{C}$		4	180	mV
Load regulation	REG _L	$I_0 = 5$ mA to 1.5A, $T_j = 25$ °C		12	360	mV
Load regulation	KEUL	$I_0 = 250$ to 750mA, $T_j = 25$ °C	—	4	180	mV
Bias current	$I_{ m Bias}$	$T_{\rm i} = 25^{\circ}{\rm C}$		4.1	8	mA
Bias current fluctuation to input	ΔI _{Bias(IN)}	$V_I = 21 \text{ to } 33\text{V}, T_j = 25^{\circ}\text{C}$			1	mA
Bias current fluctuation to load	$\Delta I_{ ext{Bias}(L)}$	$I_0 = 5 \text{mA to } 1 \text{A}, T_j = 25 ^{\circ} \text{C}$			0.5	mA
Output noise voltage	V _{no}	f = 10Hz to $100kHz$		110		μV
Ripple rejection ratio	RR	$V_I = 22 \text{ to } 32V, I_O = 100\text{mA}, f = 120\text{Hz}$	53	—		dB
Minimum input/output voltage difference	V _{DIF(min)}	$I_O = 1A, T_j = 25^{\circ}C$		2		V
Output impedance	Zo	f = 1kHz		16		mΩ
Output short-circuit current	I _{O(Short)}	$V_I = 35V, T_j = 25^{\circ}C$		700		mA
Peak output current	I _{O(Peak)}	$T_j = 25^{\circ}C$		2		A
Output voltage temperature coefficient	$\Delta V_{O}/T_{a}$	$I_0 = 5 \text{mA}, T_j = 0 \text{ to } 125^{\circ}\text{C}$	_	-1.1	_	mV/°C

Note 1) The specified condition $T_i = 25^{\circ}$ C means that the test should be carried out within so short a test time (within 10ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

Note 2) Unless otherwise specified, $V_I = 27V$, $I_O = 500 \text{mA}$, $C_I = 0.33 \mu\text{F}$ and $C_O = 0.1 \mu\text{F}$.

AN78xx series: 15W, AN78xxF series: 10.25W

• AN7820, 7820F (20V type)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Output voltage	Vo	$T_j = 25^{\circ}C$	19.2	20	20.8	V
Output voltage tolerance	Vo	$V_I = 24 \text{ to } 35\text{V}, I_O = 5\text{mA to } 1\text{A}, T_j = 0 \text{ to } 125^{\circ}\text{C}, P_D \le *$	19		21	V
Line regulation	REG _{IN}	$V_I = 23 \text{ to } 35\text{V}, T_j = 25^{\circ}\text{C}$	+	15	400	mV
Ellic regulation	KEOIN	$V_I = 26 \text{ to } 32V, T_j = 25^{\circ}C$		5	200	mV
Load regulation	REG _L	$I_0 = 5 \text{mA to } 1.5 \text{A}, T_j = 25 ^{\circ} \text{C}$		12	400	mV
Load regulation	KEOL	$I_0 = 250 \text{ to } 750 \text{mA}, T_j = 25^{\circ}\text{C}$		4	200	mV
Bias current	I_{Bias}	$T_j = 25^{\circ}C$		4.1	8	mA
Bias current fluctuation to input	$\Delta I_{Bias(IN)}$	$V_I = 23 \text{ to } 35V, T_j = 25^{\circ}C$			1	mA
Bias current fluctuation to load	$\Delta I_{Bias(L)}$	$I_0 = 5 \text{mA to } 1 \text{A}, T_j = 25 ^{\circ} \text{C}$			0.5	mA
Output noise voltage	V_{no}	f = 10Hz to 100 kHz		110	7	μV
Ripple rejection ratio	RR	$V_I = 24 \text{ to } 34V, I_0 = 100\text{mA}, f = 120\text{Hz}$	53			dB
Minimum input/output voltage difference	$V_{\text{DIF}(\text{min})}$	$I_0 = 1A, T_j = 25^{\circ}C$		2		V
Output impedance	Zo	f = 1kHz	1	22		mΩ
Output short-circuit current	I _{O(Short)}	$V_I = 35V, T_j = 25^{\circ}C$		700	ALL OF THE PROPERTY OF THE PRO	mA
Peak output current	I _{O(Peak)}	$T_j = 25^{\circ}C$		2.0	U_~'	A
Output voltage temperature coefficient	$\Delta V_{O}/T_{a}$	$I_0 = 5 \text{mA}, T_i = 0 \text{ to } 125^{\circ}\text{C}$		~ 1.2	+	mV/°C

Note 1) The specified condition $T_i = 25^{\circ}$ C means that the test should be carried out within so short a test time (within 10ms) that the characteristic value drift due to the chip junction temperature rise can be ignored. Note 2) Unless otherwise specified, $V_I = 29V$, $I_O = 500 mA$, $C_I = 0.33 \mu F$ and $C_O = 0.1 \mu F$.

AN7824, 7824F (24V type)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Output voltage	v_{o}	$T_j = 25^{\circ}C$	23	24	25	V
Output voltage tolerance	Vo	$V_1 = 28 \text{ to } 38\text{V}, I_0 = 5\text{mA to } 1\text{A},$ $T_j = 0 \text{ to } 125^{\circ}\text{C}, P_D \le *$	22.8		25.2	V
Line regulation	REGIN	$V_1 = 27 \text{ to } 38\text{V}, T_1 = 25^{\circ}\text{C}$		18	480	mV
Ente regulation	KEOIN	$V_1 = 30 \text{ to } 36\text{ V}$, $T_j = 25^{\circ}\text{C}$		6	240	mV
Load regulation	REG _L &	$T_0 = 5 \text{mA to } 1.5 \text{A}, T_j = 25 ^{\circ} \text{C}$		12	480	mV
Load regulation	REOL	$I_0 = 250$ to 750mA, $T_j = 25$ °C		4	240	mV
Bias current	IBias	$T_{\rm i} = 25^{\circ}{\rm C}$		4.1	8	mA
Bias current fluctuation to input	$\Delta I_{Bias(IN)}$	$V_I = 27 \text{ to } 38V, T_j = 25^{\circ}C$			1	mA
Bias current fluctuation to load	$\Delta I_{Bias(L)}$	$I_O = 5$ mA to 1A, $T_j = 25$ °C			0.5	mA
Output noise voltage	V_{no}	f = 10Hz to $100kHz$		170		μV
Ripple rejection ratio	RR	$V_I = 28 \text{ to } 38V, I_O = 100\text{mA}, f = 120\text{Hz}$	50			dB
Minimum input/output voltage difference	V _{DIF(min)}	$I_0 = 1A, T_j = 25^{\circ}C$		2		V
Output impedance	Zo	f = 1kHz		28		mΩ
Output short-circuit current	I _{O(Short)}	$V_I = 38V, T_j = 25^{\circ}C$		700		mA
Peak output current	I _{O(Peak)}	$T_j = 25^{\circ}C$		2		A
Output voltage temperature coefficient	$\Delta V_{O}/T_{a}$	$I_0 = 5 \text{mA}, T_j = 0 \text{ to } 125^{\circ}\text{C}$		-1.4		mV/°C

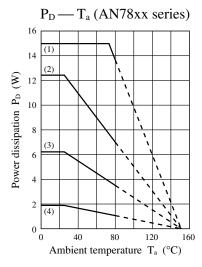
Note 1) The specified condition $T_i = 25^{\circ}$ C means that the test should be carried out within so short a test time (within 10ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

AN78xx series: 15W, AN78xxF series: 10.25W

Note 2) Unless otherwise specified, $V_I = 33V$, $I_O = 500 \text{mA}$, $C_I = 0.33 \mu\text{F}$ and $C_O = 0.1 \mu\text{F}$.

AN78xx series: 15W, AN78xxF series: 10.25W

■ Main Characteristic Curve



Thermal resistance value: $R_{th(j-c)} = 5^{\circ}C/W \text{ (max.)}$

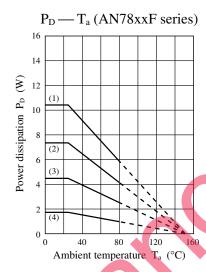
 $R_{th(j-a)} = 65^{\circ}C/W \text{ (max.)}$

Installation condition to heat sink Tightening torque 6kg·cm Heat radiation compound used

(1) Infinite heat sink: 15.0W (2) 5°C/W heat sink: 12.5W

(3) 15°C/W heat sink: 6.3W

(4) Without heat sink: 1.923W



Thermal resistance value: $R_{th(j-c)} = 12.2^{\circ}C/W \text{ (max.)}$

 $R_{th(j-a)} = 65$ °C/W (max.)

Installation condition to heat sink Tightening torque 6kg-cm

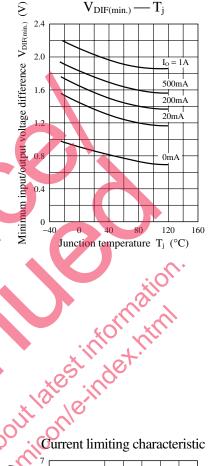
Heat radiation compound used

(1) Infinite heat sink: 10.25W

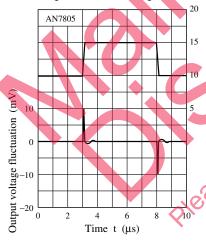
(2) 5°C/W heat sink: 7.3W

(3) 15°C/W heat sink: 4.5W

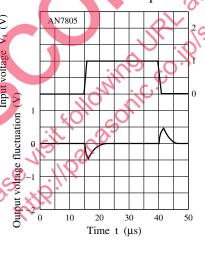
(4) Without heat sink: 1.923W

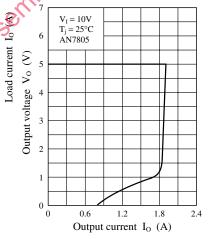


Input transient response

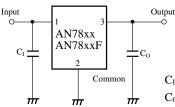


Load transient response





■ Basic Regulator Circuit



 C_{I} : C_{I} is necessary when the input line is long.

C_O: C_O improves the transient response.

■ Usage Notes

1. Cautions for a basic circuit

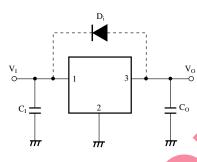


Figure 1

- C_I : When a wiring from a smoothing circuit to a three-pin regulator is long, it is likely to oscillate in output. A capacitor of $0.1\mu F$ to $0.47\mu F$ should be connected near an input pin.
- C_O : When any sudden change of load current is likely to occur, connect an electrolytic capacitor of $10\mu F$ to $100\mu F$ to improve a transitional response of output voltage.
- D_i: Normally unnecessary. But add it in the case that there is a residual voltage at the output capacitor Co even after switching off the supply power because a current is likely to flow into an output pin of the IC and damage the IC.

2. Other caution items

1) Short-circuit between the input pin and GND pin

If the input pin is short-circuitted to GND or is cut off when a large capacitance capacitor has been connected to the IC's load, a voltage of a capacitor connected to an output pin is applied between input/output of the IC and this likely results in damage of the IC. It is necessary, therefore, to connect a diode, as shown in figure 2, to counter the reverse bias between input/output pins.

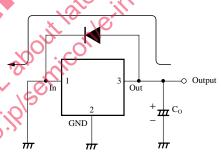


Figure 2

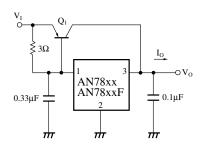
2) Floating of GND pin

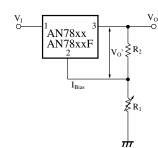
If a GND pin is made floating in an operating mode, an unstabilized input voltage is outputted. In this case, a thermal protection circuit inside the IC does not normally operate. In this state, if the load is short-circuited or overloaded, it is likely to damage the IC.

■ Application Circuit Examples

1. Current bootstrap circuit

2. Adjustable output regulator





$$V_{\rm O} = V_{\rm O}' + \left(I_{\rm Bias} + \frac{V_{\rm O}'}{R_2}\right) R_1$$

Note) $V_{\rm O}$ varies due to sample to sample variation of $I_{\rm Bias}.$

Never fail to adjust individually with R₁.

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